Call for Papers

Third International Workshop on Requirements Patterns (RePa’13)

Tuesday July 16, 2013, Rio de Janeiro, Brazil.

In conjunction with the 21th IEEE Requirements Engineering Conference

Getting requirements right is critical to the success of just about any software development project, and yet oftentimes challenging and in need of a large amount of knowledge and experience. "Patterns" have been used to capture knowledge of software development, concerning software architectures, designs, and more recently requirements engineering too. This workshop provides an open forum for researchers and practitioners to exchange ideas and experience, regarding pattern-based approaches to capturing, organizing, and reusing all aspects of requirements engineering-related knowledge, from both product and process perspectives.

RePa’13 Workshop invites two types of submissions: pattern and technical papers. The accepted papers will be available in a proceedings published by the IEEE Digital Library.

Pattern Papers

A pattern paper presents one or more related requirements process/product patterns, including, but not limited to:

- Requirements modeling patterns
- Requirements engineering process/activities patterns
- Application/domain-specific requirements patterns
- Application/domain-independent requirements patterns
- Functional requirements patterns
- Non-functional requirements patterns
- Requirements to architecture/design mapping patterns
- Goal patterns
- Social aspect patterns
- Scenario patterns (e.g. use cases, user stories)
- Workflow patterns
- Business patterns
- Analysis patterns
- Problem patterns (e.g. anti-patterns, mis-use patterns, fault patterns, attack patterns)

Technical Papers

A technical paper may be a full or position research paper, an experience report, an empirical study, or a case study that reports findings on requirements pattern-related topics, including, but not limited to:

- Pattern capturing
- Pattern harvesting and mining
- Pattern cataloging
- Pattern organization
- Pattern searching, identification, and selection
- Pattern reuse and application
- Pattern quality
- Pattern management
- Tool support

For more information and submission

Submission: by Apr. 19, 2013

www.utdallas.edu/~supakkul/repa13